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Patent Application

Inventor(s): Nemecek, et al.

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Examiner: Proctor, Jason Scott

Application No.: 10/004,197

Title: IN-CIRCUIT EMULATOR WITH GATEKEEPER BASED HALT CONTROL

Form 1449

U.S. Patent Documents


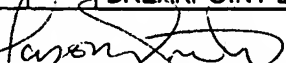
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Examiner 	Date Considered 2/2/2007	

Examiner: initial citation considered. Draw line through citation if not in conformance and not considered.
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